## Notice of References Cited Application/Control No. 10/519,065 Applicant(s)/Patent Under Reexamination VAN KESTEREN, HANS WILLE Examiner Henok G. Heyi Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,384,758 A	01-1995	Matsumoto, Hiroyuki	369/13.41
*	В	US-5,691,072 A	11-1997	Izumi et al.	428/819
*	С	US-5,756,202 A	05-1998	Van Kesteren et al.	428/332
*	D	US-5,814,400 A	09-1998	Kirino et al.	428/332
*	E	US-5,965,286 A	10-1999	Ohnuki et al.	428/823.1
*	F	US-6,030,716 A	02-2000	Izumi et al.	428/819
*	G	US-6,122,228 A	09-2000	Shimazaki et al.	369/13.07
*	Н	US-6,150,038 A	11-2000	Hirokane et al.	428/819.2
*	1	US-6,307,816 B1	10-2001	Nishimura, Naoki	369/13.07
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.